

*Proceedings*

**The 22<sup>nd</sup> IEEE International Symposium  
on Defect and Fault-Tolerance  
in VLSI Systems**

**DFT 2007**

**26–28 September 2007  
Rome, Italy**



Los Alamitos, California  
Washington • Tokyo



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IEEE International Symposium on Defect and Fault Tolerance  
in VLSI Systems 2007

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